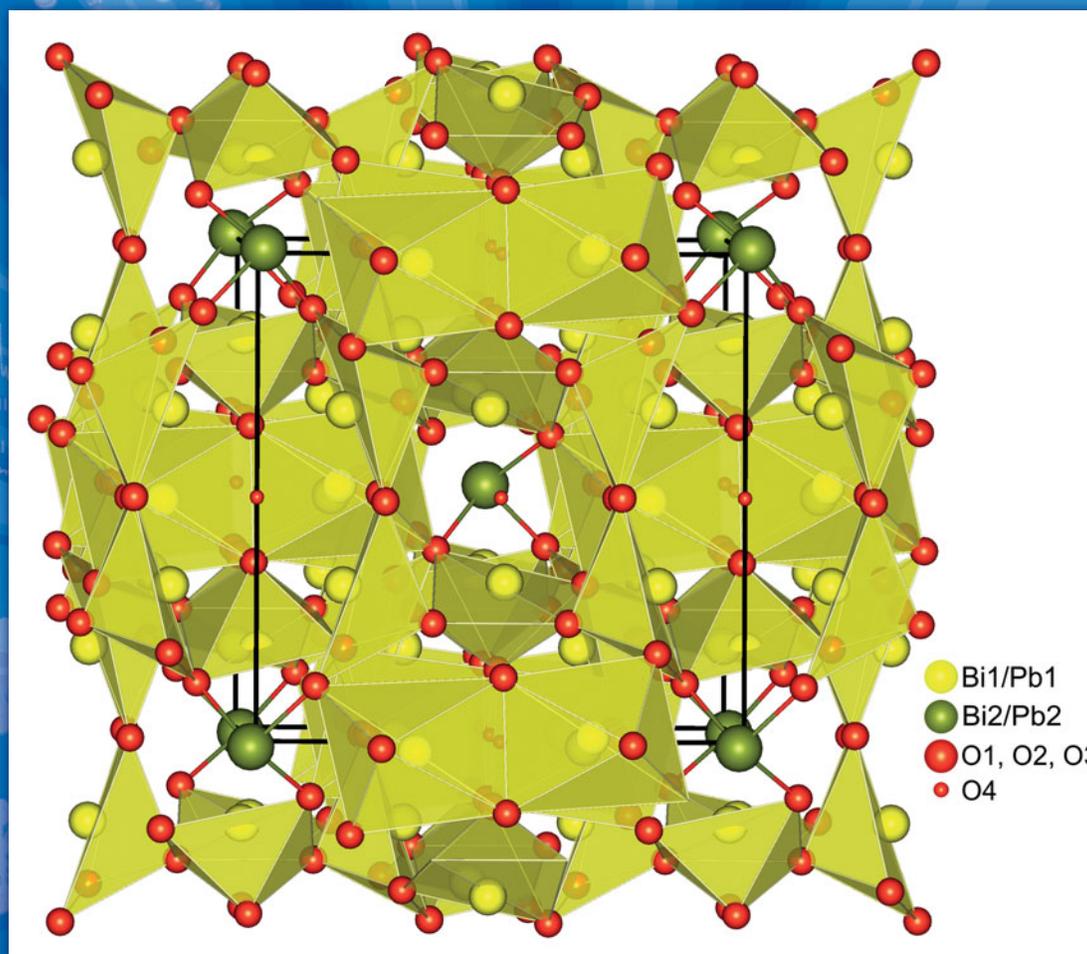


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On the cover: The polyhedral presentation of (Bi₂₃.68Pb_{0.32})(Bi_{1.28}Pb_{0.72})O_{38.48} compound. (Courtesy of Aleksandra Dapčević, Dejan Poletić, and Ljiljana Karanović).

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